

#### **General Description**

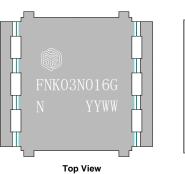
- Trench Power MOSFET technology
- $\bullet$  Low  $R_{\text{DS(ON)}}$  at 10 V  $_{\text{GS}}$
- Low Gate Charge

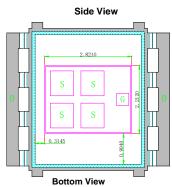
#### **Product Summary**

 $V_{\text{DS}} \\$ 30V I<sub>D</sub> (at V<sub>GS</sub>=10V) 130A  $R_{DS(ON)}$  (at  $V_{GS}$ =10V) < 1.6mΩ

# Schematic diagram







**TDHD4**\*5

### **Applications**

- · Load switch, battery switch
- Automotive applications
- Uninterruptible power supply

Orderable Part Number	umber Packa		Form	Minimum	nimum Order Quantity		
FNK03N016G	TDHD		Tape & Reel		•		
Absolute Maximum Ratings T <sub>A</sub> =2	5°C unless o	therwise note	d				
Parameter		Symbol	Maxin	Maximum			
Drain-Source Voltage		V <sub>DS</sub>	30		V		
Gate-Source Voltage		$V_{GS}$	± 20	)	V		
Continuous Drain Current <sub>G</sub>		I <sub>D</sub>	130		А		
Pulsed Drain Current <sup>C</sup>		I <sub>DM</sub>	520				
Avalanche energy L=0.5mH <sup>C</sup>		E <sub>AS</sub>	270		mJ		
Power Dissipation <sup>B</sup>		P <sub>D</sub>	96		W		
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150		°C		
Thermal Characteristics							
Parameter		Symbol	Тур	Max	Units		
Maximum Junction-to-Ambient A	t ≤ 10s		25	30	°C/W		
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	40	50	°C/W		
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1.3	1.8	°C/W		



# **FNK03N016G**

#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units				
STATIC PARAMETERS										
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	30			V				
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ =30V, $V_{GS}$ =0V			1	μΑ				
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±10V			±100	nA				
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1.0	1.5	2.5	V				
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =25A		1.3	1.6	mΩ				
		$V_{GS}$ =4.5V, $I_D$ =20A		2.1	2.5	mΩ				
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A		150		S				
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			1	V				
Is	Maximum Body-Diode Continuous Current				50	Α				
DYNAMIC	PARAMETERS									
C <sub>iss</sub>	Input Capacitance			5100		pF				
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =15V, f=1MHz		1550		pF				
C <sub>rss</sub>	Reverse Transfer Capacitance			220		pF				
$R_g$	Gate resistance	f=1MHz			3.5	Ω				
SWITCHI	NG PARAMETERS									
Q <sub>g</sub> (10V)	Total Gate Charge			80	100	nC				
Q <sub>g</sub> (4.5V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =20A		34	54	nC				
$Q_{gs}$	Gate Source Charge	VGS-10V, VDS-13V, ID-20A		11		nC				
$Q_{gd}$	Gate Drain Charge	7		12		nC				
t <sub>D(on)</sub>	Turn-On DelayTime			8		ns				
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}=10V, V_{DS}=15V, R_{L}=0.75\Omega,$		7		ns				
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}=3\Omega$		90		ns				
t <sub>f</sub>	Turn-Off Fall Time	7		20		ns				
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=500A/μs		24		ns				
$Q_{rr}$	Body Diode Reverse Recovery Charge	l <sub>F</sub> =20A, di/dt=500A/μs		65		nC				

A. The value of  $R_{\text{BJA}}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{BJA}}$   $\bowtie$  10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^{\circ}$  C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

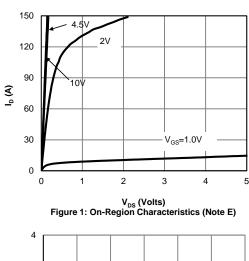
C. Single pulse width limited by junction temperature  $T_{J(MAX)}$ =150 $^{\circ}$  C. D. The  $R_{\text{eJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{eJC}}$  and case to ambient.

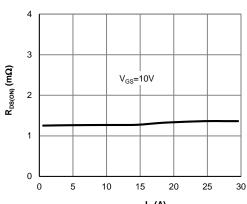
E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.</li>
 F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsin k, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.
 G. The maximum current rating is package limited.

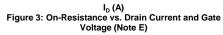
H. These tests are performed with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.

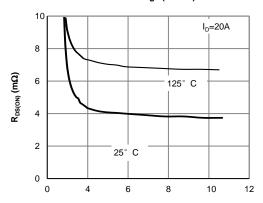


#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

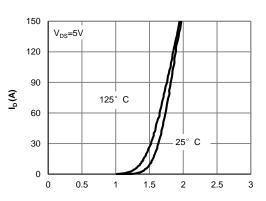




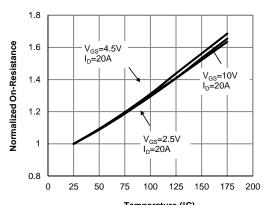




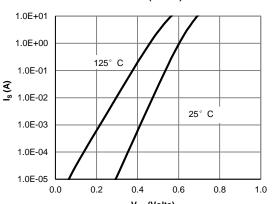
V<sub>GS</sub> (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage
(Note E)



 $V_{GS}$  (Volts) Figure 2: Transfer Characteristics (Note E)



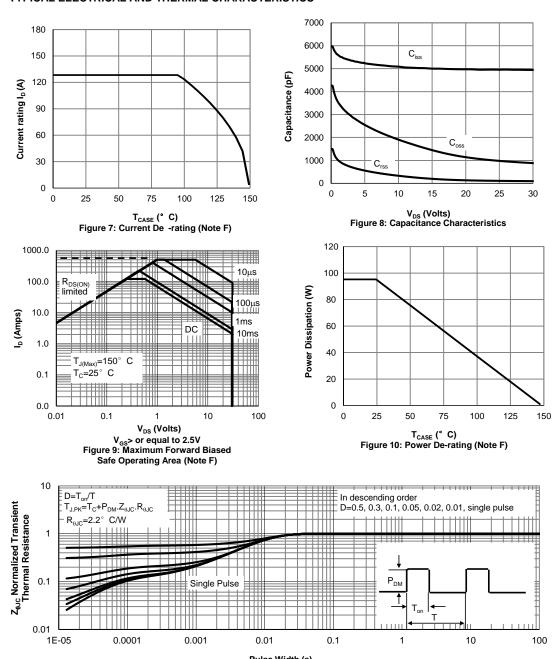
Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature (Note E)



V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)



#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



Figure A: Gate Charge Test Circuit & Waveforms

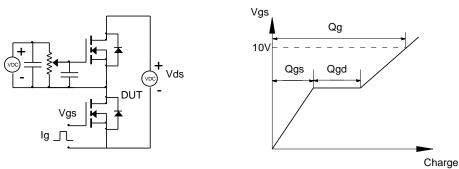


Figure B: Resistive Switching Test Circuit & Waveforms

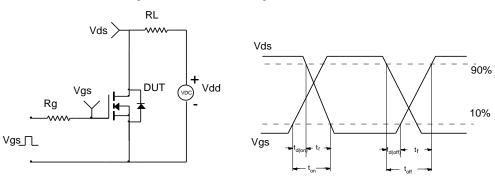


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

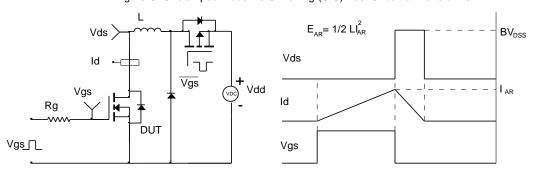
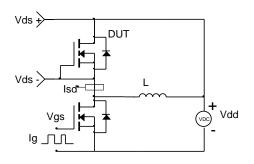
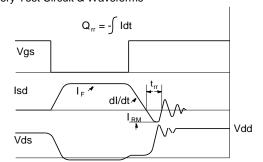


Figure D: Diode Recovery Test Circuit & Waveforms



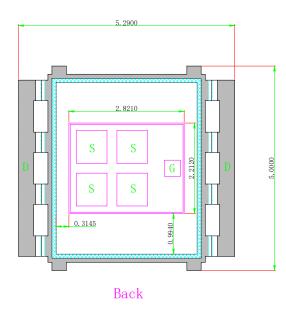


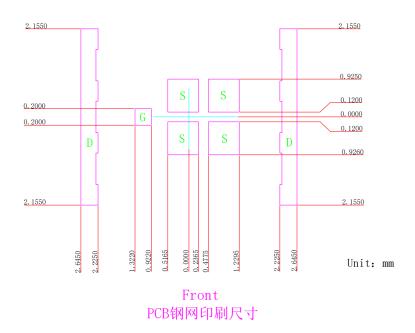


## **TDHD5\*6 Package Information**

Unit: mm









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